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DEBYE

Simulation program for powder diffraction
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Reference:

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Lyngby, Denmark

General:

The Debye simulation program calculates the XRPD pattern from a crystalline sample by summing over all interatomic distances as stated by the Debye equation (Debye, 1915, Ann. Phys. 46: 809). The crystallographic information can be imported from a cif and modified if necessary. Additional information about particle shape, size and size distribution can be supplied. The min, max and step in 2θ as well as the wavelength can be altered to agree with experimental XRPD data. Finally the simulated data can be convoluted with a polarisation function, a pseudo-Voigt type instrument profile (Wertheim et al., 1974, Rev. Sci. Instrum. 45(11): 1369) and functions related to the Guinier diffraction geometry and absorption in cylindrical samples.

Thermal parameters:

The program only works with isotropic thermal parameters, and these are averaged to one per atom type. If the crystallographic information read from a cif does not contain a Biso, it will be calculated from the anisotropic thermal parameters in case these are given, otherwise the program defaults to Biso=0.

Limitations:

The program is presently limited to five different atom types.

GUI:

The Windows GUI for the Debye program offers the opportunity to open an experimental XRPD pattern, simulate or open an earlier simulated diffractogram for comparison, and do a fit. The progress of the simulation and fitting can be followed in the lower text window while the diffraction patterns are shown in the upper graphical window. It is possible to zoom in the graphical window by holding down the left mouse button and dragging a window of the desired size.

Fitting:

During the fitting procedure the simulated diffractogram is scaled using either an ordinary scale factor, an overall temperature factor, or both. The background is modelled as a Chebyshev polynomial with a user-specified number of parameters (between 0 and 14). A 2θ zero shift can be manually added during the fitting procedure. The fitted parameters and their standard deviations are written on the rec file (see files below) and can be viewed via patterns, table output.

Based on the fitted background it is possible to calculate the crystallinity, the fraction of intensity resulting from the simulated crystalline part of the sample, between any two values of 2θ .

N.B. The crystallinity calculation is only valid if the background represents amorphous scattering from the sample only.

How to install:

Copy debye.exe and DebyeHelp.txt (this file) into a common directory and make the appropriate correction to the

winpow.ini file to define the default directory and the path leading to notepad.exe or some other text editor.

Files:

To do the simulations a name.rec input file in ascii format is needed. The input file can be constructed from scratch using the commands listed below. It is, however, much easier to import the crystallographic information from a cif and define the desired structural parameters via the GUI menus. If an experimental diffraction pattern is imported for fitting it is possible to obtain the following output files:

%name.out	List file summarising the simulation
%name.tab	Tabulated summary of simulation and fitting
%name.xy	Simulated diffractogram
%name.sum	2theta, experimental pattern, simulated and fitted pattern, difference, background.
%name.fdp	Pair distribution function. Only for the first atom type.

Multiple simulations:

For more time-consuming calculations the Debye program offers the opportunity to run a series of simulations without having to start each simulation manually in the GUI. For this purpose all the rec files must first be constructed along with a file called "anything.mlt" containing the names of all the rec files to run, one name per line, eg:

```
name1.rec
name2.rec
name3.rec
```

Under file, open project choose the mlt file and select project, calculation.

Shortcut keys:

up arrow	Zoom out in graphical window
down "	Zoom in
left "	Move zoom window left
right "	Move zoom window right
F1	Return graphical window to full view
F2	Return graphical and text windows to original size
F3	Project, calculate
F4	Patterns, fit pattern
F5	File, save project as
F6	Project, edit files
F7	Project, edit structure
F8	Project, edit instructions
ctrl-T	Patterns, table output

List of records in the name.rec input file for the Debye simulations:

Required records:

SPGR Space group symbol in the old Hermann-Mauguin notation with inversion centre at origo, e.g. P 21 21 21, P -3, P 63/M, F d d d. For rhombohedral space groups use the hexagonal setting.

CELL Cell dimensions

11-20	cell (1)	a [A]
21-30	cell (2)	b [A]
31-40	cell (3)	c [A]
41-50	cell (4)	alpha [deg]
51-60	cell (5)	beta [deg]
61-70	cell (6)	gamma [deg]

XYZ Atomic coordinates

11-14	atomname	Atom identifier
18-20	atype	Atomic number
21-30	x	Fractional coordinates

31-40 y " "
 41-50 z " "
 51-60 sof Site occupancy factor
 61-70 Biso Isotropic temperature factor coefficient $B=U8PI^{**2}$

Optional records:

TITL 11-78 Title of the job

PWDT 11-70 Name of experimental diffraction pattern file

FRMT Input data format (optional)
 11-15 1 - gdf (Huber)
 2 - txt (Bruker)
 3 - udf (Philips)
 4 - xrdml (PANalytical)
 5 - xy (general)
 6 - std (general)

ELAM Wavelengths (default: 1.54059, 0, 0 - CuKalpha1)
 11-20 lambda(1) [A]
 21-30 lambda(2) [A]
 31-40 lambda(3) lambda2/lambda1 intensity ratio

ANOM Anomalous dispersion corrections (defaults to MoKalpha, CuKalpha or CoKalpha depending on which wavelength is closest)
 11-14 atomname Atom identifier
 21-30 fp f'
 31-40 fpp f''

DDIS Distance calculation accuracy (default: 100)
 11-20 disacc Reciprocal of the distance calculation accuracy [A-1]

DSHA Particle shape (default: 1, 3)
 11-15 crysttype 1 - box
 2 - cylinder
 3 - ellipsoid
 16-20 cylaxis 1 - a*
 2 - b
 3 - a*xb

DABC Particle size
 If crysttype = 1: number of cells along the a-, b- and c-axis (default: 10, 10, 10)
 If crysttype = 2: cylinder dimensions [A] (default: 100., 50.)
 If crysttype = 3: ellipsoid dimension [A] (default: 50., 50., 50.)
 11-20 ncella/cylen/ellips1
 21-30 ncellb/cylrad/ellips2
 31-40 ncellc/ellips3

DPSD Particle size distribution (PSD) (default: 0, 3, 1)
 11-15 ptype 0 - do not apply PSD
 1 - apply PSD
 16-20 psample number of sizes sampled on either side of the mean (max 9)
 NB! Only sizes 1.0+-0.1 psample, eg. 0.8, 0.9, 1.0, 1.1 and 1.2 times the input size (psample=2)
 21-25 distype 1 - Weibull mass distribution
 2 - Gaussian "
 3 - Uniform "
 4 - User defined "

- DUS1 User defined mass distribution coefficients required for distype=4 (default: 0., . . . , 0.)
 11-20 puser(-9) mass fraction of particles
 21-30 puser(-8) with a size defined as
 31-40 puser(-7) 0.1, 0.2, 0.3, 0.4 etc times the input size
 41-50 puser(-6)
 51-60 puser(-5)
 61-70 puser(-4)
 71-80 puser(-3)
- DUS2 User defined mass distribution coefficients
 11-20 puser(-2)
 21-30 puser(-1)
 31-40 puser(0)
 41-50 puser(1)
 51-60 puser(2)
 61-70 puser(3)
 71-80 puser(4)
- DUS3 User defined mass distribution coefficients
 11-20 puser(5)
 21-30 puser(6)
 31-40 puser(7)
 41-50 puser(8)
 51-60 puser(9)
- DTTH 2theta interval information and scale factor
 (default: 5., 50., 0.02, 0)
 11-20 ttmin 2thetamin [deg]
 21-30 ttmax 2thetamax [deg]
 31-40 tt dif 2thetastep [deg]
 41-50 ttsca =0 - intensity per unit cell is output
 >0 - intensity output for ttsca unit cells
 <0 - simulated pattern will be scaled to lmax=-ttsca
- DCOR Intensity corrections (default: 1, 0, 0, 0, 0, 1.)
 11-15 corrpola 0 - no polarisation correction
 1 - polarisation correction
 16-20 corrpola 0 - no instrument profile
 1 - pseudo-Voigt instrument peak profile correction
 21-25 corraabs 0 - no absorption correction
 1 - correct for absorption in cylindrical sample
 26-30 corrguin 0 - no guinier correction
 1 - correct for 45 deg Guinier tangent angle
 31-35 corrauto 0 - no auto divergence slit
 1 - auto divergence slit correction
 36-45 corrmur value of muR for absorption correction
- DPRO pseudo-Voigt peak profile parameters (gL+(1-g)G)
 (default: 0., 0., 0.01, 0.5, 0., 0.)
 11-20 uu FWHM
 21-30 vv (Caglioti et al., 1958, Nucl. Instrum. Methods 3(4): 223)
 31-40 ww
 41-50 g1 pseudo-Voigt mixing parameter
 51-60 g2 $g = g_1 + g_2(2\theta) + g_3(2\theta)^2$
 61-70 g3 (Hill and Howard, 1985, J. Appl. Cryst. 18(3): 173)

Records added by the fitting routine:

- SCAL Scale factors (default: 1., 0.)
 11-22 scal scale factor from fitting

23-32	ovrl	overall temperature factor
ZETT	2theta zero shift (default: 0.)	NB! Not refined
11-20	zett	2theta zero shift
BKGR	Chebyshev background parameters (default: 0., ..., 0.)	
	NB! Three records, 0-14 Chebyshev parameters	
11-20	bkg1/bkg6/bkg11	
21-30	bkg2/bkg7/bkg12	
31-40	bkg3/bkg8/bkg13	
41-50	bkg4/bkg9/bkg14	
51-60	bkg5/bkg10	
DCRY	Crystallinity (default: 5., 50., 0.)	
11-20	crysttmin	[deg]
21-30	crysttmax	[deg]
31-40	xtallinity	Crystallinity calculated between crysttmin and crysttmax
DVAL	Fitting results	
11-20	fitpatrval	Pattern R-value from fit
21-30	fitpatwrval	Weighted pattern R-value
31-40	fitpatgof	Goof from fit
41-47	fitpatnpar	Number of fitted parameters
48-54	nstep	Number of 2theta steps